

May 19, 2008

FREESCALE SEMICONDUCTOR, INC. LAW DEPARTMENT 7700 WEST PARMER LANE MD:TX32/PL02

**AUSTIN TX 78729** 

Patent No.

: 6,937,047 B2

Inventor(s)

Tu-Anh Tran, et al.

Issued For : August 30, 2005 INTEGRATED CIRCUIT WITH TEST

PAD STRUCTURE AND METHOD OF

TESTING

Doc. No.

SC12598TK

To Whom It May Concern:

The Certificate of Correction issued on <u>May 20, 2008</u>, issued in error, in that error(s) was made in identifying the patent number and/or keying text/corrections, i.e.:

The issue date in the heading of cofc has been incorrectly entered in the heading of the issued cofc. A superseding cofc will be issued to correct the patent issue date to read --August 30, 2005-

Therefore, a certificate of correction will be issued to correct (supersede) the Certificate of Correction containing error(s), made during preparation of the Certificate of Correction, as noted above.

No further response is required, from applicants (attorney). However, errors discovered by attorney, other than as noted and described above, should be noted on *a copy* of the Certificate of Correction that was issued in error, accompanied by a signed transmittal letter and submitted directed to this Branch.

Antonio Johnson (703) 308-9390 ext. 111 For Mary F. Diggs, Supervisor Decisions & Certificates of Correction Branch (703) 305-8309 / 703-308-9390 ext. 125 cbn